## Notice of References Cited Application/Control No. 10/029,292 Examiner Krisna Lim Applicant(s)/Patent Under Reexamination RHEE ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,742,116	05-2004	Matsui et al.	713/171
	В	US-6,330,022	12-2001	Seligmann, Doree	348/14.08
	С	US-6,760,750	07-2004	Boneh et al.	709/204
	D	US-6,559,863	05-2003	Megiddo, Nimrod	715/753
	Е	US-6,219,045	04-2001	Leahy et al.	715/757
	F	US-5,978,835	11-1999	Ludwig et al.	709/204
	G	US-6,343,314	01-2002	Ludwig et al.	709/204
	Н	US-5,347,306	09-1994	Nitta, Tohei	348/14.1
	_	US-5,999,208	12-1999	McNerney et al.	348/14.08
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	7				
	0					
	Р					
	ď			•	,	
	R					
	S					
	T					·

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.